



Bib Data Sheet



**UNITED STATES DEPARTMENT OF
COMMERCE**
Patent and Trademark Office

Address: COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, D.C. 20231

FILE COPY

SERIAL NUMBER 09/579,542	FILING DATE 05/26/2000 RULE -	CLASS 216	GROUP ART UNIT 1746	ATTORNEY DOCKET NO. TSMC2000-079	
APPLICANTS Cheng Chung Lin, Taipei City, TAIWAN; Lain-Jong Li, Hualien, TAIWAN;					
** CONTINUING DATA ***** NON ^{MS} LV					
** FOREIGN APPLICATIONS ***** VCNEL LV					
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 08/09/2000					
Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 (a-d) conditions <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after met Verified and Acknowledged <u>Allowance</u> <u>LV</u> Examiner's Signature Initials		STATE OR COUNTRY TAIWAN	SHEETS DRAWING 2	TOTAL CLAIMS 20	INDEPENDENT CLAIMS 3
ADDRESS George O Saile 20 McIntosh Drive Poughkeepsie, NY 12603					
TITLE Method to improve stability and reliability of CVD low K dielectric					
FILING FEE RECEIVED 690	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		

GEORGE O. SAILE & ASSOCIATES

20 MCINTOSH DRIVE

POUGHKEEPSIE, NY 12603

RECEIVED
FILE COPY

TS00-079



August 14, 2000

To: Assistant Commissioner of Patents
Office of Initial Patent Examination
Customer Service Center
Washington, D.C. 20231

From: George O. Saile

Subject: Serial No.: 09/579,542
Filing Date: 05/26/2000
Inventor: C. C. Lin, et al
Title: Method to Improve Stability and Reliability of CVD Low K Dielectric

RECEIVED
AUG 31 2000
TOLSON MAIL ROOM

REQUEST TO CORRECT FILING RECEIPT

Dear Sir:

On the copy of the enclosed Filing Receipt, there are errors in the Title. Acronyms should be capitalized. The corrected Title reads: **Method to improve stability and reliability of CVD low K dielectric.**

Please make the necessary changes to correct the errors on the Filing Receipt.

If there are any questions, please contact the undersigned attorney at (845) 452-5863. Thank you for your attention to this matter.

Respectfully Submitted,

George O. Saile

George O. Saile, Reg. No. 19,572

AUG. 13 2000

FILING RECEIPT



OC00000005309773

UNITED STATES DEPARTMENT OF COMMERCE
Patent and Trademark OfficeAddress: ASSISTANT SECRETARY AND
COMMISSIONER OF PATENT AND TRADEMARKS
Washington, D.C. 20231

APPLICATION NUMBER	FILING DATE	GRP ART UNIT	FIL FEE REC'D	ATTY. DOCKET NO	DRAWINGS	TOT CLAIMS	IND CLAIMS
09/579,542	05/26/2000	1746	690	TSMC2000-079	2	20	3

George O Saile
20 McIntosh Drive
Poughkeepsie, NY 12603

Date Mailed: 08/09/2000

Receipt is acknowledged of this nonprovisional Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. **If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Customer Service Center. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the PTO processes the reply to the Notice, the PTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).**

Applicant(s)

Cheng Chung Lin, Taipei City, TAIWAN;
Lain-Jong Li, Hualien, TAIWAN;

Continuing Data as Claimed by Applicant

Foreign Applications

If Required, Foreign Filing License Granted 08/09/2000

Title

Method to improve stability and reliability of cvd low k dielectric

Preliminary Class

216

Data entry by : BARNES, CAROL

Team : OIPE

Date: 08/09/2000



RECEIVED
AUG 31 2000
TO L/00 MAIL ROOM